



NSWC CRANE

— 1-2 August 2017 —





MICROELECTRONICS INTEGRITY MEETING AGENDA

1 AUGUST 2017



0700 Registration

0800 Introduction Mr. Brian Stuffle, Manager, Flight System Division, NSW Crane

0815 Janna Foxx (SSTM), Deputy Technical Director, NSW Crane

0830 Keynote Mr. Kerry Bernstein, Program Manager, Defense Advanced Research Projects Agency

0915 Panel 1: **Challenges in Today's Workforce** (Chair – Mrs. Shana Goodman)

Speakers:

- Matthew Kay Flight Systems Division Failure Analysis Chief Engineer, NSW Crane
- Dr. James C. Conwell, President, Rose-Hulman Institute of Technology
- Mr. Benjamin Harkness, Director, Global Deterrence and Defense Department, NSW Crane

1045 Break

1100 Panel 2: **Radiation Hardening and Trust in a COTS Age** (Chair – Dr. Matthew Halstead)

Speakers:

- Mr. Dave Emily, Strategic Systems Program
- Dr. Jonathan Ahlbin, EEE Parts and Processes Branch Lead, Missile Defense Agency
- Dr. Matthew Gadlage, Radiation Sciences Branch, NSW Crane

1230 Break for Lunch

1400 Panel 3: **Counterfeit Detection and Risk Mitigation in IT Hardware** (Chair – Mr. Fred Schipp)

Speakers & Topics:

- Mr. Tom Sharpe, SMT Corporation Executive Vice President
- Sandra McLeod, Cisco
- Dan Hadsell, Cisco
- Mr. Bill Shelton, Juniper Networks Director, Federal Certifications and Policy

1600 No Host Social/Networking – Crowne Plaza Downtown

1700 Poster Sessions and Electronic Test System Demonstrations

There will be a number of counterfeit mitigation displays/demonstrations at this year's Microelectronics Integrity Meeting, including Battelle (Barricade), Nokomis (ADEC), Sandia (PSA), ChromoLogic (QuanTEK), Applied DNA Sciences, PFP Cyber, and SMT Corporation. Details are being finalized.

1800 Poster Winners Announced

1815 Conclude Day 1